

Docket No.: 0039-7632-0X

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

RE: Application Serial No.: 09/531,163

Applicants: Hiroyuki YANO, et al.

Filing Date: March 17, 2000

For: AQUEOUS DISPERSION, AQUEOUS DISPERSION

FOR CHEMICAL MECHANICAL POLISHING USED FOR MANUFACTURE OF SEMICONDUCTOR DEVICES, METHOD FOR MANUFACTURE OF

SEMICONDUCTOR DEVICES, AND METHOD FOR FORMATION OF EMBEDDED WIRING

Group Art Unit: 1765 Examiner: DEO, D.

SIR:

Attached hereto for filing are the following papers:

Amendment and Request for Reconsideration (6 pp.)

Certified English Translation

Certified English Translation of Experiment Report (3 pp.)

Experiment Report (3 pp.)

Our check in the amount of \$0.00 is attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,

MAIER & NEUSTADT, P.C.

Norman F. Oblon

Registration No. 24,618

RECEIVED

**OBLON** 

SPIVAK

McClelland Maier

> NEUSTADT P.C.

ATTORNEYS AT LAW

NORMAN F. OBLON (703) 413-3000

NOBLON@OBLON.COM

STEFAN U. KOSCHMIEDER, Ph.D.

REGISTERED PATENT AGENT (703) 412-6463

SKOSCHMIEDER@OBLON.COM

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22850

(703) 413-3000 (phone) (703) 413-2220 (fax) Stefan U. Koschmieder, Ph.D. Registration No. 50,238

SEP 2 3 7002 W

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## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF:

REALITICATION OF.

HIROYUKI YANO ET AL. : GROUP ART UNIT: 1765

SERIAL NO: 09/531,163

FILED: MARCH 17, 2000 : EXAMINER: DEO, D.

FOR: AQUEOUS DISPERSION, AQUEOUS

DISPERSION FOR CHEMICAL
MECHANICAL POLISHING USED
FOR MANUFACTURE OF SEMICONDUCTOR DEVICES, METHOD
FOR MANUFACTURE OF SEMICONDUCTOR DEVICES, AND
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EMBEDDED WIRING

SEP 2 4 2002 TC 1700

AMENDMENT AND REQUEST FOR RECONSIDERATION

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Responsive to the Office Action of June 21, 2002, Applicants respectfully request reconsideration of the above-identified application in view of the following amendment and remarks.

## **REMARKS**

Applicants thank Examiner Deo and the Examiner's Supervisor Benjamin Utech for the helpful and courteous discussion of July 18, 2002. During the discussion, the Examiner's Supervisor suggested that the submission of a Declaration providing a comparison of the polishing performance of the presently claimed invention with the polishing performance of the compositions disclosed in the Ronay patent may be sufficient for overcoming the rejection